


SHEET 1 OF 1

<b>INFORMATION DISCLOSURE CITATION</b> PTO-1449	<b>CUSTOMER NUMBER</b>  26615	ATTORNEY'S DKT No. H1105D	APPLICATION No. 10/602,061				
		APPLICANT(S) Shibly S. AHMED et al.					
		FILING DATE June 24, 2003	GROUP 2812				
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
RP	Copy of co-pending U.S. Serial No. 10/770,011; Bin Yu et al.; filed February 3, 2004; entitled "Double-Gate Semiconductor Device with Gate Contacts Formed Adjacent Sidewalls of a Fin", 27 pages.						
EXAMINER <i>for Pompey</i>				DATE CONSIDERED <i>6-24-04</i>			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

<b>INFORMATION DISCLOSURE CITATION</b> PTO-1449	 <b>26615</b> <small>PATENT INFORMATION OFFICE</small>	ATTORNEY'S DKT NO. H1105D	APPLICATION NO. Unassigned
		APPLICANT(S) Shilby S. AHMED et al.	
		FILING DATE June 24, 2003	GROUP Unassigned

U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
RP	Digh Hisamoto et al., "FinFET-A Self-Aligned Double-Gate MOSFET Scalable to 20 nm," IEEE Transactions on Electron Devices, Vol. 47, No. 12, December 2000, pages 2320-2325.
RP	Yang-Kyu Choi et al., "Sub-20nm CMOS FinFET Technologies," 2001 IEEE, IEDM, pages 421-424.
RP	Xuejue Huang et al., "Sub-50 nm P-Channel FinFET," IEEE Transactions on Electron Devices, Vol. 48, No. 5, May 2001, pages 880-886.
RP	Xuejue Huang et al., "Sub 50-nm FinFET: PMOS," 1999 IEEE, IEDM, pages 67-70.
RP	Yang-Kyu Choi et al., "Nanoscale CMOS Spacer FinFET for the Terabit Era," IEEE Electron Device Letters, Vol. 23, No. 1, January 2002, pages 25-27.
RP	U.S. Application Serial No. 10/290,330, filed November 8, 2002, entitled "DOUBLE-GATE SEMICONDUCTOR DEVICE," Bin Yu et al., 20 page specification, 11 sheets of drawings.
RP	U.S. Application Serial No. 10/348,758, filed January 23, 2003, entitled "GERMANIUM MOSFET DEVICES AND METHODS FOR MAKING SAME," Judy Xilin An et al., 22 page specification, 29 sheets of drawings.

EXAMINER <i>Ron Pompey</i>	DATE CONSIDERED <i>6-24-04</i>
----------------------------	--------------------------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).



<b>INFORMATION DISCLOSURE CITATION</b> PTO-1449		<b>CUSTOMER NUMBER</b>  26615	ATTORNEY'S DKT No. H1105D		APPLICATION No. 10/602,061		
			APPLICANT(S) Shibly S. AHMED et al.				
			FILING DATE June 24, 2003		GROUP 2812		
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
RP	2003/0151077	8-14-03	Mathew et al.	257	250		
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER <i>Ron Pompey</i>				DATE CONSIDERED <i>6-24-04</i>			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).



SHEET 1 OF 1

<b>INFORMATION DISCLOSURE CITATION</b> PTO-1449		<b>CUSTOMER NUMBER</b>  26615	ATTORNEY'S DKT No. H1105D		APPLICATION No. 10/602,061		
			APPLICANT(S) Shibly S. AHMED et al.				
			FILING DATE June 24, 2003		GROUP 2812		
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
RP	6,610,576 B2	8/26/03	Nowak				
RP	6,528,381 B2	3/4/03	Lee et al.				
RP	6,458,662 B1	10/1/02	Yu				
RP	6,300,182 B1	10/9/01	Yu				
RP	6,159,782	12/12/00	Xiang et al.				
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER			DATE CONSIDERED				
Ken Pompey			6-20-04				

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).



SHEET 1 OF 1

<b>INFORMATION DISCLOSURE CITATION</b> PTO-1449	<b>CUSTOMER NUMBER</b>  26615	ATTORNEY'S DKT NO. H1105D	APPLICATION No. 10/602,061				
		APPLICANT(S) Shibly S. Ahmed et al.					
		FILING DATE June 24, 2003	GROUP 2812				
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
RP	6,483,171 B1	11/19/2002	Forbes et al.	257	627		
RP	6,396,108 B1	05/28/2002	Krivokapic et al.	257	365		
RP	5,315,143	05/24/1994	Tsuji	257	351		
RP	6,611,029 B1	08/26/2003	Ahmed et al.	257	365		
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER <i>Rm Pompey</i>				DATE CONSIDERED <i>6-20-04</i>			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).



<b>INFORMATION DISCLOSURE CITATION</b> PTO-1449		Customer Number: <b>26615</b>	ATTORNEY'S DKT NO. H1105D	APPLICATION NO. 10/602,061			
			APPLICANT(S) Shibly S. AHMED et al.				
			FILING DATE June 24, 2003	GROUP Unassigned			
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
RP	6,525,403 B2	02-25-03	Inaba et al.	257	618	09-24-01	
<b>FOREIGN PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
RP	U.S. Patent Application Publication No. US 2003/0042531 A1; March 6, 2003; Lee et al.						
RP	U.S. Patent Application Publication No. US 2003/0113970 A1; June 19, 2003; Fried et al.						
EXAMINER <i>Ron Pompey</i>				DATE CONSIDERED <i>6-24-03</i>			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).